

Description

The HSTP75NF75 uses advanced trench technology and design to provide excellent R_{DS(ON)} with low gate charge. It can be used in a wide variety of applications.



TO-220

General Features

V_{DS} =80V,I_D =96A

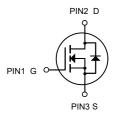
 $R_{DS(ON)}$ < 7.2m Ω @ V_{GS} =10V

Application

High efficiency switch mode power supplies

Power factor correction

Electronic lamp ballast



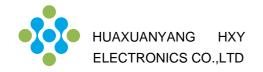
N-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Units Tube
HSTP75NF75	TO-220C	HXY MOSFET	50

Absolute Maximum Ratings@T_j=25°C(unless otherwise specified)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	80	V
Gate-Source Voltage	Vgs	±20	V
Drain Current-Continuous	I _D	96	А
Drain Current-Continuous(T _C =100℃)	I _D (100℃)	67	А
Pulsed Drain Current	I _{DM}	368	А
Maximum Power Dissipation	P _D	146	W
Derating factor	-	1.06	W/℃
Single pulse avalanche energy (Note 5)	E _{AS}	625	mJ
Thermal Resistance,Junction-to-Case ^(Note 2)	Rejc	1.02	°C/W
Operating Junction and Storage Temperature Range	T_{J} , T_{STG}	-55 To 150	°C



Electrical Characteristics T_J = 25°C unless otherwise noted

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{DS} = 0, I_{D} = 250 \mu A$	80			٧	
Gate Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.0		4.0		
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
		$V_{DS} = 80 \text{ V} , V_{GS} = 0 \text{ V}$			1	μA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 ^{\circ}\text{C}$			50		
		$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 150 ^{\circ}\text{C}$			250	1	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 10 \text{ V}, V_{GS} = 10 \text{ V}$	96			А	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 10 V, I _D = 40 A		6.2	7.2	mΩ	
Forward Transconductance ^a	g _{fs}	V _{DS} = 15 V, I _D = 40 A		13		S	
Dynamic ^b	•		•	•			
Input Capacitance	C _{iss}			6395			
Output Capacitance	C _{oss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$		386		pF	
Reverse Transfer Capacitance	C _{rss}			255			
Total Gate Charge ^c	Qg			116			
Gate-Source Charge ^c	Q _{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 40 \text{ A}$		27		nC	
Gate-Drain Charge ^c	Q_{gd}			39			
Turn-On Delay Time ^c	t _{d(on)}			22			
Rise Time ^c	t _r	$V_{DD} = 30 \text{ V, R}_{L} = 2.5 \Omega$		50		ns	
Turn-Off Delay Time ^c	t _{d(off)}	$I_D \approx 40 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		65			
Fall Time ^c	t _f			22			
Source-Drain Diode Ratings and Cha	racteristics 7	r _C = 25 °C ^b	•	•			
Continuous Current	I _S				96	^	
Pulsed Current	I _{SM}				368	Α	
Forward Voltage ^a	V _{SD}	I _F = 40 A, V _{GS} = 0 V		0.89		V	
Reverse Recovery Time	t _{rr}			41		NS	
Peak Reverse Recovery Current	I _{RM(REC)}	I _F = 10 A, dI/dt = 100 A/µs		3.0		Α	
Reverse Recovery Charge	Q _{rr}			86		nC	

Notes:

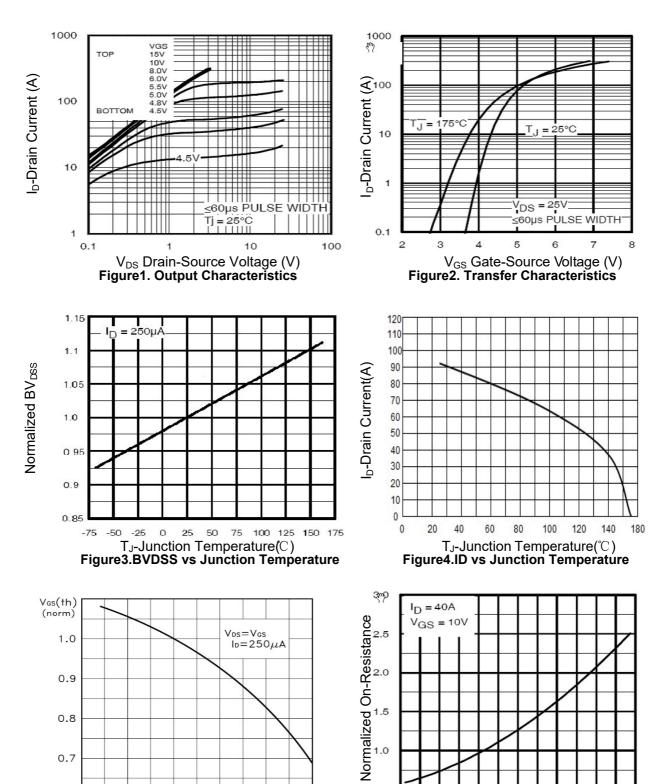
a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

c. Independent of operating temperature.



Typical Characteristics



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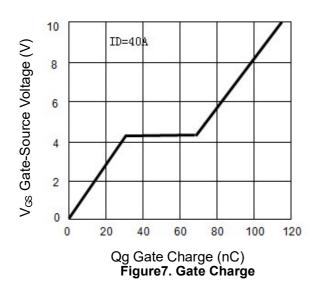
T_J-Junction Temperature(°C) Figure 5.VGS(th) vs Junction Temperature

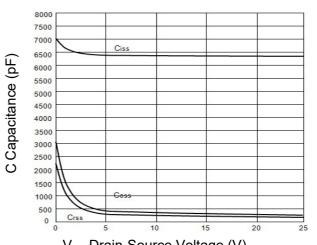
0.7

-60 -40 -20 0 20 40 60 80 100120140160180

T_J-Junction Temperature(C)

Figure 6. Rdson Vs Junction Temperature





V_{DS} Drain-Source Voltage (V) Figure8. Capacitance vs Vds

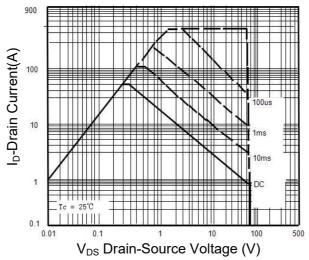


Figure 9. Safe Operation Area

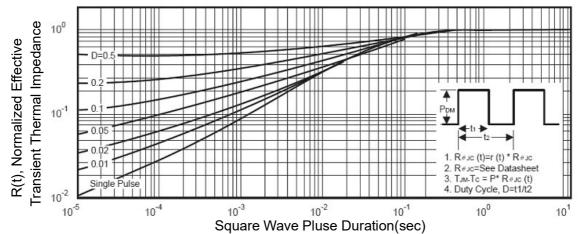
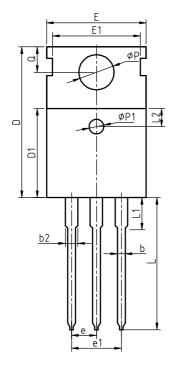
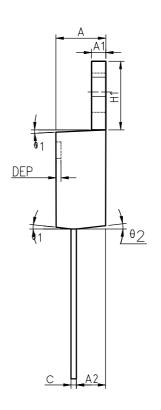


Figure 11. Normalized Maximum Transient Thermal Impedance

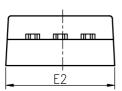


Package Information TO-220C





COMMON DIMENSIONS



SYMBOL	MIN	NOM	MAX	MIN	NOM	MAX
Α	4.40	4.57	4.70	0. 173	0.180	0.185
A1	1.27	1.30	1.33	0.050	0.051	0.052
A2	2.35	2.40	2.50	0.093	0.094	0.098
b	0.77	0.80	0.90	0.030	0.031	0.035
b2	1.17	1. 27	1.36	0.046	0.050	0.054
С	0.48	0.50	0.56	0.019	0.020	0.022
D	15.40	15.60	15.80	0.606	0.614	0.622
D1	9.00	9. 10	9. 20	0.354	0.358	0.362
DEP	0.05	0.10	0.20	0.002	0.004	0.008
E	9.80	10.00	10.20	0.386	0.394	0.402
E1	ı	8. 70	-	-	0.343	-
E2	9.80	10.00	10.20	0.386	0.394	0.402
е		2.54	BSC		0.100	BSC
e1		5.08	BSC		0.200	BSC
H1	6.40	6.50	6.60	0. 252	0.256	0.260
L	12.75	13.50	13.65	0.502	0.531	0.537
L1	-	3.10	3.30	-	0.122	0.130
L2		2.50	REF		0.098	REF
Р	3.50	3.60	3.63	0.138	0.142	0.143
P1	3.50	3.60	3.63	0.138	0.142	0.143
Q	2.73	2.80	2.87	0. 107	0.110	0.113
θ 1	5°	7°	9°	5°	7°	9°
θ 2	1°	3°	5°	1°	3°	5°
θ 3	1°	3°	5°	1°	3°	5°

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